

Scanning Probe Microscopy School

It is with the greatest pleasure that we announce the NanoInnovation School on Scanning Probe Microscopy (SPM), which will be held as a satellite event of NanoInnovation 2020. After the success of the school on electron microscopy during the past edition of NanoInnovation, the topic of the this year school will be focused on the most recent SPM techniques, including atomic force microscopy (AFM), scanning tunneling microscopy (STM), scanning near field optical microscopy (SNOM) and other scanning probe methods, for advanced functional characterization (electric, magnetic, mechanical, chemical...) of materials at the nanometer scale. Further information and a preliminary list of topics and speakers can be found here:

<https://www.nanoinnovation2020.eu/home/index.php/programme/schools-and-courses/nanoinnovation-spm-school>

The NanoInnovation 2020 SPM School is mainly intended for graduate and PhD students as well as young scientists interested in deepening their knowledge about advanced SPM methods, but it is also open to all researchers and scientists who are involved in the different fields characterizations methods for nanotechnology and nanosciences.

The event will be held in mixed modality, i.e., both online and in attendance. As for all the NanoInnovation events, the attendance to the NanoInnovation 2020 SPM School is free and the interested attendees are requested to register using the NanoInnovation website selecting the option "SPM School" in the online form, indicating also the preferred attendance modality.

For further information and details, do not hesitate to contact Dr. Daniele Passeri, Chair of the SPM School, at his mail address daniele.passeri@uniroma1.it.

Preliminary list of topics and speakers:

- *Scanning tunneling microscopy* (Fabrizio BOBBA)
- *Data analysis in SPM* (Francesco MARINELLO)
- *Multimodal AFM* (Ricardo GARCIA)
- *Exploration of nanoscale thermal transport and thermoelectric phenomena in 2D materials via scanning probes* (Oleg KOLOSOV)
- *Atomically Precise Molecular Design: Insights From Sub-molecular Resolution Scanning Probe Microscopy* (Samuel JARVIS)
- *SCM and SSRM application in Nanoelectronics (carrier profiling)* (Umberto CELANO)
- *C-AFM for 2D materials* (Umberto CELANO)
- *Nanoscale 3D imaging of physical properties of materials* (Oleg KOLOSOV)
- *3D tomographic AFM using Scalpel SPM* (Umberto CELANO)
- *MFM and PFM characterisation of ferromagnetic, ferroelectric and multiferroic nanostructures* (Bernard NYSTEN)
- *Characterization of nanomagnets by Advanced Magnetic Force Microscopy* (Agustina ASENJO)
- *Application of MFM for bio-nanotechnology* (Gunjan AGARWAL)